# 

# 2:1 DIFFERENTIAL-TO-LVPECL MULTIPLEXER

# ICS858018

# **General Description**



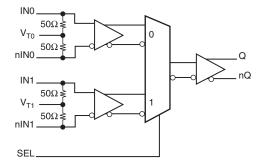
The ICS858018 is a high performance 2:1 Differential-to-LVPECL Multiplexer and is a member of the HiPerClockS<sup>™</sup> family of high performance clock solutions from IDT. The ICS858018 differential inputs have internal termination resistors and when

used in conjunction with the  $V_{T0}/V_{T1}$  pins, allow the inputs to interface with several differential signal types. The ICS858018 is packaged in a small, 3mm x 3mm VFQFN package, making it ideal for use on space-constrained boards.

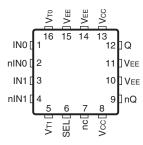
## **Features**

- One LVPECL output
- INx/nINx pairs can accept the following differential input levels: LVPECL, LVDS, CML
- Maximum output frequency: 2GHz
- Propagation delay: 700ps (maximum)
- Part-to-part skew: 250ps (maximum)
- Supply voltage range: (LVPECL)  $V_{CC} = 2.375V$  to 3.63V,  $V_{EE} = 0V$ (ECL)  $V_{CC} = 0V$ ,  $V_{EE} = -3.63V$  to -2.375V
- -40°C to 85°C ambient operating temperature
- Available in both standard (RoHS 5) and lead-free (RoHS 6) packages

# **Block Diagram**



# **Pin Assignment**



#### ICS858018

16-Lead VFQFN 3mm x 3mm x 0.925mm package body G Package Top View

Number	Name	Туре		Description
1	IN0	Input		Non-inverting differential LVPECL clock input.
2	nIN0	Input		Inverting differential LVPECL clock input.
3	IN1	Input		Non-inverting differential LVPECL clock input.
4	nIN1	Input		Inverting differential LVPECL clock input.
5, 16	$V_{T1,}V_{T0}$	Input		Input for termination. Both IN and nIN inputs are terminated to this pin. See Application Information section, <i>Differential Input with Built-in 50</i> $\Omega$ <i>Termination Interface.</i>
6	SEL	Input	Pullup	Select pin. LVCMOS/LVTTL interface levels.
7	nc	Unused		No connect.
8, 13	V <sub>CC</sub>	Power		Power supply pins.
9, 12	nQ, Q	Output		Differential output pair. LVPECL/ECL interface levels.
10, 11, 14, 15	$V_{EE}$	Power		Negative supply pins.

# **Table 1. Pin Descriptions**

NOTE: Pullup refers to internal input resistors. See Table 2, Pin Characteristics, for typical values

# **Table 2. Pin Characteristics**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
R <sub>PULLUP</sub>	Input Pullup Resistor			37		kΩ

# Table 3. Truth Table

	Inputs					puts
IN0	nIN0	IN1	nIN1	SEL	Q	nQ
0	1	Х	Х	0	0	1
1	0	Х	Х	0	1	0
Х	Х	0	1	1	0	1
Х	Х	1	0	1	1	0

# **Absolute Maximum Ratings**

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics or AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V <sub>CC</sub>	-0.5V to + 4.0V
Inputs, V <sub>I</sub>	-0.5V to V <sub>CC</sub> + 0.5V
Outputs, I <sub>O</sub>	
Continuous Current	50mA
Surge Current	100mA
Input Current, IN/nIN	+50mA
V <sub>T</sub> Current, I <sub>VT</sub>	+100mA
Operating Temperature Range, T <sub>A</sub>	-40°C to 85°C
Storage Temperature, T <sub>STG</sub>	-65°C to 150°C
Package Thermal Impedance, $\theta_{JA}$ (Junction-to-Ambient)	88.5°C/W (0 mps)

# **DC Electrical Characteristics**

Table 4A. Power Supply DC Characteristics,  $V_{CC} = 3.3V \pm 10\%$  or  $2.5V \pm 5\%$ ,  $V_{EE} = 0V$ ,  $T_A = -40^{\circ}C$  to  $85^{\circ}C$ 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>CC</sub>	Positive Supply Voltage		2.375	3.3	3.63	V
I <sub>EE</sub>	Power Supply Current				21	mA

Table 4B. LVCMOS/LVTTL DC Characteristics, V <sub>CC</sub>	= $3.3V \pm 10\%$ or $2.5V \pm 5\%$ , $V_{EE} = 0V$ , $T_A = -40$ °C to $85$ °C
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Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V	Input High Voltage	$V_{CC} = 3.3V$	2		V <sub>CC</sub> + 0.3	V
V <sub>IH</sub> Input H	input riigh voltage	V <sub>CC</sub> = 2.5V	1.7		V <sub>CC</sub> + 0.3	V
V <sub>IL</sub> Input Low Voltage	Input Low Voltage	V <sub>CC</sub> = 3.3V	-0.3		0.8	V
	V <sub>CC</sub> = 2.5V	-0.3		0.7	V	
I <sub>IH</sub>	Input High Current	$V_{CC} = V_{IN} = 3.63V \text{ or } 2.625V$			10	μA
I <sub>IL</sub>	Input Low Current	$V_{CC}$ = 3.63V or 2.625V, $V_{IN}$ = 0V	-150			μA

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
R <sub>IN</sub>	Differential Input Resistance	INx/nINx	IN to V <sub>T</sub>	40	50	60	Ω
V <sub>IH</sub>	Input High Voltage	INx/nINx		1.2		V <sub>CC</sub>	V
V <sub>IL</sub>	Input Low Voltage	INx/nINx		0		V <sub>IH</sub> – 0.15	V
V <sub>IN</sub>	Input Voltage Swing			0.15		2.8	V
V <sub>DIFF_IN</sub>	Differential Input Voltage Swin	g		0.3		3.4	V
IN	Input Current; NOTE 1	INx/nINx				35	mA

#### Table 4C. DC Characteristics, $V_{CC} = 3.3V \pm 10\%$ or $2.5V \pm 5\%$ , $V_{EE} = 0V$ , $T_A = -40^{\circ}C$ to $85^{\circ}C$

NOTE 1: Guaranteed by design.

#### Table 4D. LVPECL DC Characteristics, $V_{CC} = 3.3V \pm 10\%$ or $2.5V \pm 5\%$ , $V_{EE} = 0V$ , $T_A = -40^{\circ}C$ to $85^{\circ}C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>OH</sub>	Output High Voltage; NOTE 1			V <sub>CC</sub> – 1.005		V
V <sub>OL</sub>	Output Low Voltage; NOTE 1			V <sub>CC</sub> – 1.78		V
V <sub>OUT</sub>	Output Voltage Swing		0.6		1.0	V
V <sub>DIFF_OUT</sub>	Differential Output Voltage Swing		1.2		2.0	V

NOTE 1: Outputs terminated with 50 $\Omega$  to V<sub>CC</sub> – 2V.

# **AC Electrical Characteristics**

Table 3. LVPECL AC Characteristics,  $V_{CC} = 3.3V \pm 10\%$  or  $2.5V \pm 5\%$ ,  $V_{EE} = 0V$ ,  $T_A = -40^{\circ}C$  to  $85^{\circ}C$ 

Parameter	Symbol		Test Conditions	Minimum	Typical	Maximum	Units
f <sub>MAX</sub> t <sub>PD</sub>	Output Frequency		$V_{OUT} \ge 450 mV$		1	2	GHz
	Propagation Delay, Differential; NOTE 1	IN0 or IN1-to-Q		350		700	ps
	Differential, NOTE T	SEL-to-Q		0.175		1.3	ns
<i>t</i> sk(i)	Input Skew; NOTE 2	-				35	ps
<i>t</i> sk(pp)	Part-to-Part Skew; NOTE 3, 4					250	ps
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fall Time		20% to 80%	75		375	ps

All parameters characterized at  $\leq$  1GHz unless otherwise noted

T<sub>A</sub>, Ambient Temperature applied using forced air flow.

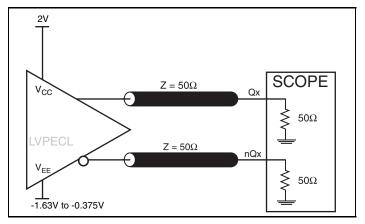
NOTE 1: Measured from the differential input crossing point to the differential output crossing point.

NOTE 2: Defined as skew between inputs measured to the same output at the same supply voltage and with equal load conditions. Measured at the output differential cross points.

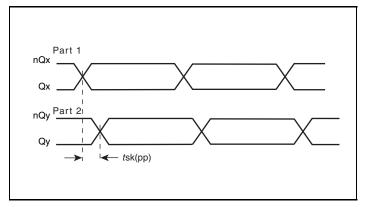
NOTE 3: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at the differential cross points.

NOTE 4: This parameter is defined in accordance with JEDEC Standard 65.

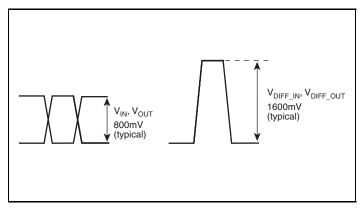
# **Parameter Measurement Information**



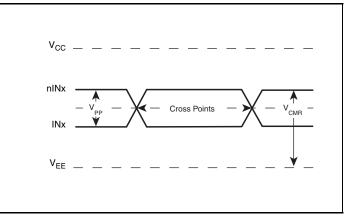
**Output Load AC Test Circuit** 



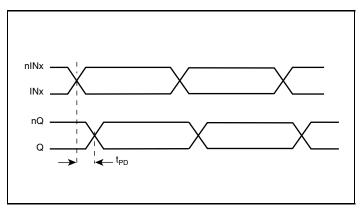
Part-to-Part Skew



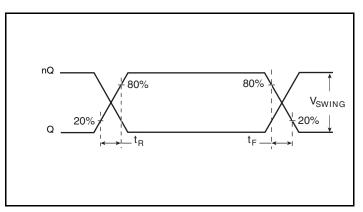
Single-ended & Differential Input Voltage Swing



#### **Differential Input Level**

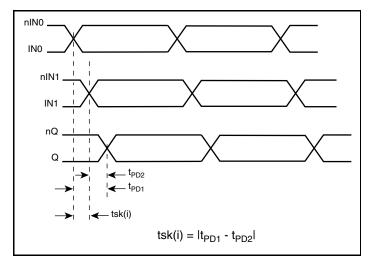


**Propagation Delay** 





# Parameter Measurement Information, continued



Input Skew

# **Application Information**

## **Recommendations for Unused Input Pins**

## Inputs:

#### **LVCMOS Control Pins**

The control pin has an internal pullup; additional resistance is not required but can be added for additional protection. A  $1k\Omega$  resistor can be used.

## 3.3V Differential Input with Built-In 50 $\!\Omega$ Termination Interface

The IN /nIN with built-in 50 $\Omega$  terminations accept LVDS, LVPECL, LVHSTL, CML, SSTL and other differential signals. Both signals must meet the V<sub>IN</sub> and V<sub>IH</sub> input requirements. *Figures 1A to 1D* show interface examples for the HiPerClockS IN/nIN input with built-in 50 $\Omega$  terminations driven by the most common driver types.

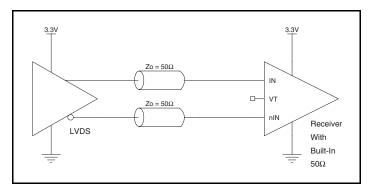


Figure 1A. HiPerClockS IN/nIN Input with Built-In 50  $\Omega$  Driven by an LVDS Driver

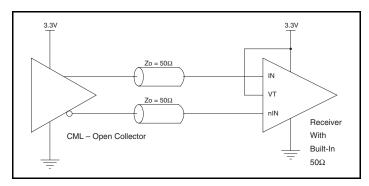


Figure 1C. HiPerClockS IN/nIN Input with Built-In 50 $\Omega$  Driven by a CML Driver

The input interfaces suggested here are examples only. If the driver is from another vendor, use their termination recommendation. Please consult with the vendor of the driver component to confirm the driver termination requirements.

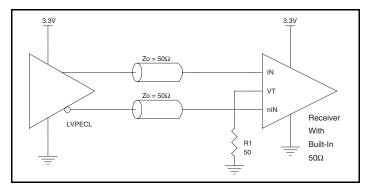


Figure 1B. HiPerClockS IN/nIN Input with Built-In 50  $\Omega$  Driven by an LVPECL Driver

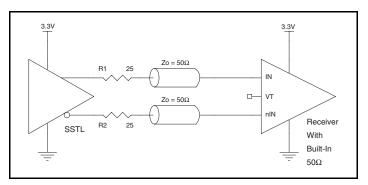


Figure 1D. HiPerClockS IN/nIN Input with Built-In 50  $\Omega$  Driven by an SSTL Driver

## 2.5V LVPECL Input with Built-In 50 $\Omega$ Termination Interface

The IN /nIN with built-in 50 $\Omega$  terminations accept LVDS, LVPECL, CML, SSTL and other differential signals. Both signals must meet the V<sub>IN</sub> and V<sub>IH</sub> input requirements. *Figures 2A to 2D* show interface examples for the HiPerClockS IN/nIN with built-in 50 $\Omega$  termination input driven by the most common driver types. The

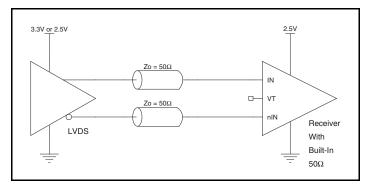


Figure 2A. HiPerClockS IN/nIN Input with Built-In 50  $\Omega$  Driven by an LVDS Driver

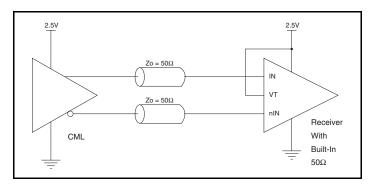


Figure 2C. HiPerClockS IN/nIN Input with Built-In 50 $\Omega$  Driven by a CML Driver

input interfaces suggested here are examples only. If the driver is from another vendor, use their termination recommendation. Please consult with the vendor of the driver component to confirm the driver termination requirements.

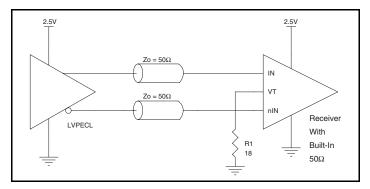


Figure 2B. HiPerClockS IN/nIN Input with Built-In 50  $\Omega$  Driven by an LVPECL Driver

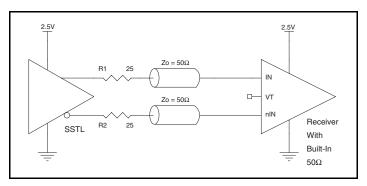


Figure 2D. HiPerClockS IN/nIN Input with Built-In 50 $\Omega$  Driven by an SSTL Driver

## 2.5V Differential Input with Built-In 50 $\!\Omega$ Termination Unused Input Handling

To prevent oscillation and to reduce noise, it is recommended to have pullup and pulldown connect to true and compliment of the unused input as shown in Figure 3A.

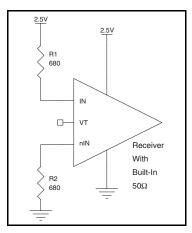


Figure 3A. Unused Input Handling

## 3.3V Differential Input with Built-In 50 $\Omega$ Termination Unused Input Handling

To prevent oscillation and to reduce noise, it is recommended to have pullup and pulldown connect to true and compliment of the unused input as shown in Figure3B.

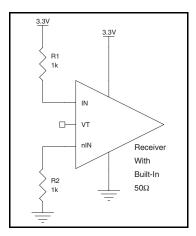


Figure 3B. Unused Input Handling

## **Termination for 3.3V LVPECL Outputs**

The clock layout topology shown below is a typical termination for LVPECL outputs. The two different layouts mentioned are recommended only as guidelines.

FOUT and nFOUT are low impedance follower outputs that generate ECL/LVPECL compatible outputs. Therefore, terminating resistors (DC current path to ground) or current sources must be used for functionality. These outputs are designed to drive  $50\Omega$ 

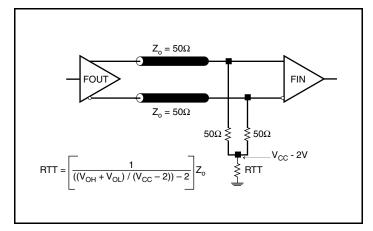


Figure 4A. 3.3V LVPECL Output Termination

transmission lines. Matched impedance techniques should be used to maximize operating frequency and minimize signal distortion. *Figures 4A and 4B* show two different layouts which are recommended only as guidelines. Other suitable clock layouts may exist and it would be recommended that the board designers simulate to guarantee compatibility across all printed circuit and clock component process variations.

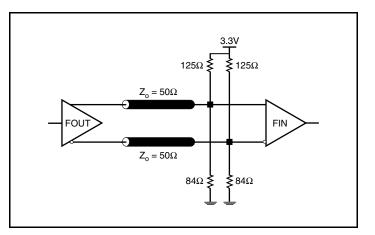


Figure 4B. 3.3V LVPECL Output Termination

## **Termination for 2.5V LVPECL Outputs**

Figure 5A and Figure 5B show examples of termination for 2.5V LVPECL driver. These terminations are equivalent to terminating 50 $\Omega$  to V<sub>CC</sub> – 2V. For V<sub>CC</sub> = 2.5V, the V<sub>CC</sub> – 2V is very close to

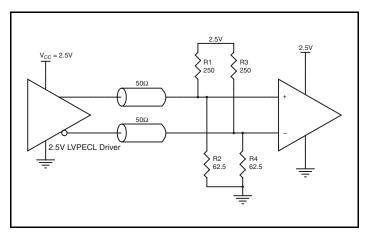


Figure 5A. 2.5V LVPECL Driver Termination Example

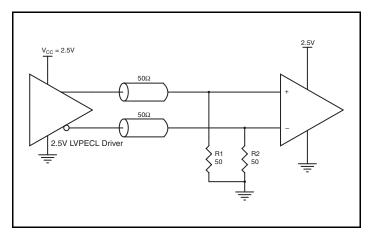


Figure 5C. 2.5V LVPECL Driver Termination Example

ground level. The R3 in Figure 5B can be eliminated and the termination is shown in *Figure 5C*.

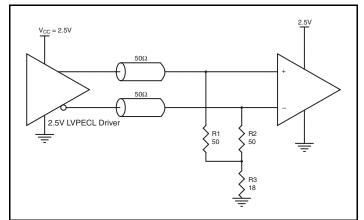
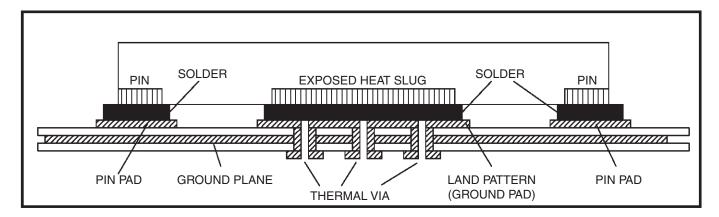


Figure 5B. 2.5V LVPECL Driver Termination Example

## **VFQFN EPAD Thermal Release Path**

In order to maximize both the removal of heat from the package and the electrical performance, a land pattern must be incorporated on the Printed Circuit Board (PCB) within the footprint of the package corresponding to the exposed metal pad or exposed heat slug on the package, as shown in *Figure 6*. The solderable area on the PCB, as defined by the solder mask, should be at least the same size/shape as the exposed pad/slug area on the package to maximize the thermal/electrical performance. Sufficient clearance should be designed on the PCB between the outer edges of the land pattern and the inner edges of pad pattern for the leads to avoid any shorts.

While the land pattern on the PCB provides a means of heat transfer and electrical grounding from the package to the board through a solder joint, thermal vias are necessary to effectively conduct from the surface of the PCB to the ground plane(s). The land pattern must be connected to ground through these vias. The vias act as "heat pipes". The number of vias (i.e. "heat pipes") are application specific and dependent upon the package power dissipation as well as electrical conductivity requirements. Thus, thermal and electrical analysis and/or testing are recommended to determine the minimum number needed. Maximum thermal and electrical performance is achieved when an array of vias is incorporated in the land pattern. It is recommended to use as many vias connected to ground as possible. It is also recommended that the via diameter should be 12 to 13mils (0.30 to 0.33mm) with 1oz copper via barrel plating. This is desirable to avoid any solder wicking inside the via during the soldering process which may result in voids in solder between the exposed pad/slug and the thermal land. Precautions should be taken to eliminate any solder voids between the exposed heat slug and the land pattern. Note: These recommendations are to be used as a guideline only. For further information, please refer to the Application Note on the Surface Mount Assembly of Amkor's Thermally/Electrically Enhance Leadframe Base Package, Amkor Technology.



#### Figure 6. P.C. Assembly for Exposed Pad Thermal Release Path – Side View (drawing not to scale)

# **Power Considerations**

This section provides information on power dissipation and junction temperature for the ICS858018. Equations and example calculations are also provided.

#### 1. Power Dissipation.

The total power dissipation for the ICS858018 is the sum of the core power plus the power dissipated in the load(s). The following is the power dissipation for  $V_{CC} = 3.3V + 10\% = 3.63V$ , which gives worst case results.

NOTE: Please refer to Section 3 for details on calculating power dissipated in the load.

- Power (core)<sub>MAX</sub> = V<sub>CC\_MAX</sub> \* I<sub>EE\_MAX</sub> = 3.63V \* 21mA = 76.23mW
- Power (outputs)<sub>MAX</sub> = 27.83mW w/Loaded Output pair

Total Power\_MAX = 76.23mW + 27.83mW = 104.06mW

#### 2. Junction Temperature.

Junction temperature, Tj, is the temperature at the junction of the bond wire and bond pad and directly affects the reliability of the device. The maximum recommended junction temperature for HiPerClockS devices is 125°C.

The equation for Tj is as follows: Tj =  $\theta_{JA}$  \* Pd\_total + T<sub>A</sub>

Tj = Junction Temperature

 $\theta_{JA}$  = Junction-to-Ambient Thermal Resistance

Pd\_total = Total Device Power Dissipation (example calculation is in section 1 above)

T<sub>A</sub> = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance  $\theta_{JA}$  must be used. Assuming no air flow and a multi-layer board, the appropriate value is 88.5°C/W per Table 6 below.

Therefore, Tj for an ambient temperature of 85°C with all outputs switching is:

 $85^{\circ}C + 0.0104W * 88.5^{\circ}C/W = 94.2^{\circ}C$ . This is well below the limit of  $125^{\circ}C$ .

This calculation is only an example. Tj will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (multi-layer).

#### Table 6. Thermal Resistance $\theta_{JA}$ for 16 Lead VFQFN, Forced Convection

$\theta_{JA}$ vs. Air Flow						
Meters per Second	0	1	2.5			
Multi-Layer PCB, JEDEC Standard Test Boards	88.5°C/W	77.3°C/W	69.4°C/W			

#### 3. Calculations and Equations.

The purpose of this section is to derive the power dissipated into the load. LVPECL output driver circuit and termination are shown in *Figure 7*.

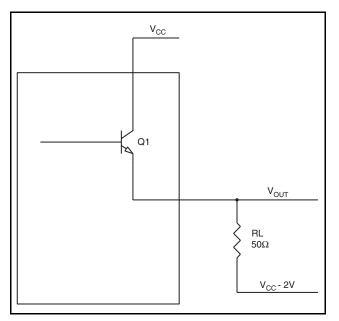


Figure 7. LVPECL Driver Circuit and Termination

To calculate worst case power dissipation into the load, use the following equations which assume a 50 $\Omega$  load, and a termination voltage of V<sub>CC</sub> – 2V.

- For logic high,  $V_{OUT}$  =  $V_{OH\_MAX}$  =  $V_{CC\_MAX}$  1.005V  $(V_{CC\_MAX} V_{OH\_MAX})$  = 1.005V
- For logic low,  $V_{OUT} = V_{OL\_MAX} = V_{CC\_MAX} 1.78V$ ( $V_{CC\_MAX} - V_{OL\_MAX}$ ) = 1.78V

Pd\_H is power dissipation when the output drives high.

Pd\_L is the power dissipation when the output drives low.

 $\begin{array}{l} \mathsf{Pd}_{-}\mathsf{H} = [(\mathsf{V}_{\mathsf{OH}\_\mathsf{MAX}} - (\mathsf{V}_{\mathsf{CC}\_\mathsf{MAX}} - 2\mathsf{V}))/\mathsf{R}_{\mathsf{L}}] * (\mathsf{V}_{\mathsf{CC}\_\mathsf{MAX}} - \mathsf{V}_{\mathsf{OH}\_\mathsf{MAX}}) = [(2\mathsf{V} - (\mathsf{V}_{\mathsf{CC}\_\mathsf{MAX}} - \mathsf{V}_{\mathsf{OH}\_\mathsf{MAX}}))/\mathsf{R}_{\mathsf{L}}] * (\mathsf{V}_{\mathsf{CC}\_\mathsf{MAX}} - \mathsf{V}_{\mathsf{OH}\_\mathsf{MAX}}) = [(2\mathsf{V} - 1.005\mathsf{V})/50\Omega] * 1.005\mathsf{V} = \textbf{20mW} \end{array}$ 

 $\begin{array}{l} Pd\_L = [(V_{OL\_MAX} - (V_{CC\_MAX} - 2V))/R_{L}] * (V_{CC\_MAX} - V_{OL\_MAX}) = [(2V - (V_{CC\_MAX} - V_{OL\_MAX}))/R_{L}] * (V_{CC\_MAX} - V_{OL\_MAX}) = [(2V - 1.78V)/50\Omega] * 1.78V = \textbf{7.83mW} \end{array}$ 

Total Power Dissipation per output pair = Pd\_H + Pd\_L = 27.83mW

# **Reliability Information**

#### Table 7. $\theta_{\text{JA}}$ vs. Air Flow Table for a 16 Lead VFQFN

$\theta_{JA}$ vs. Air Flow						
Meters per Second	0	1	2.5			
Multi-Layer PCB, JEDEC Standard Test Boards	88.5°C/W	77.3°C/W	69.4°C/W			

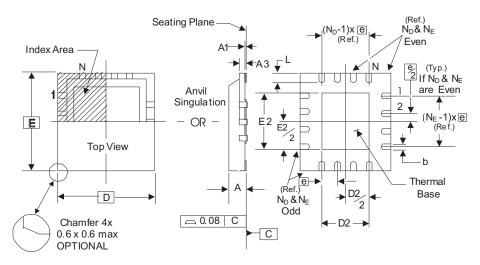
### **Transistor Count**

The transistor count for ICS858018 is: 109

Pin Compatible with SY58011U

# Package Outline and Package Dimensions

#### Package Outline - K Suffix for 16 Lead VFQFN



#### Table 8. K Package Dimensions for 16 Lead VFQFN

All Dimensions in Millimeters				
Symbol	Minimum	Maximum		
N	16			
Α	0.80	1.0		
A1	0	0.05		
A3	0.25 Reference			
b	0.18	0.30		
е	0.50 Basic			
D, E	3.0			
D2, E2	1.00	1.80		
L	0.30	0.50		
N <sub>D</sub> N <sub>E</sub>	4.0			

Reference Document: JEDEC Publication 95, MO-220

# **Ordering Information**

#### **Table 9. Ordering Information**

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
858018AK	018A	16 Lead VFQFN	Tube	-40°C to 85°C
858018AKT	018A	16 Lead VFQFN	2500 Tape & Reel	-40°C to 85°C
858018AKLF	18AL	"Lead-Free" 16 Lead VFQFN	Tube	-40°C to 85°C
858018AKLFT	18AL	"Lead-Free" 16 Lead VFQFN	2500 Tape & Reel	-40°C to 85°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

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